
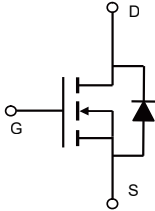


<p><b>Description</b></p> <p>These N-Channel enhancement mode power field effect transistors are using <b>shielded gate trench DMOS</b> technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and with stand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.</p> <p><b>Features</b></p> <ul style="list-style-type: none"> <li>◆ 40V,80A,<math>R_{DS(on).max}=3.55m\Omega@V_{GS} = 10V</math></li> <li>◆ Improved dv/dt capability</li> <li>◆ Fast switching</li> <li>◆ 100% EAS Guaranteed</li> <li>◆ Green device available</li> </ul> <p><b>Applications</b></p> <ul style="list-style-type: none"> <li>◆ Motor Drives</li> <li>◆ UPS</li> <li>◆ DC-DC Converter</li> </ul>	<p><b>Product Summary</b></p> <table> <tr> <td><math>V_{DSS}</math></td> <td>40V</td> </tr> <tr> <td><math>R_{DS(on).max}@V_{GS}=10V</math></td> <td>3.55m<math>\Omega</math></td> </tr> <tr> <td><math>I_D</math></td> <td>80A</td> </tr> </table> <p><b>Pin Configuration</b></p> <div style="display: flex; justify-content: space-around; align-items: center;"> <div style="text-align: center;">  <p>TO-252</p> </div> <div style="text-align: center;">  <p>Schematic</p> </div> </div>	$V_{DSS}$	40V	$R_{DS(on).max}@V_{GS}=10V$	3.55m $\Omega$	$I_D$	80A
$V_{DSS}$	40V						
$R_{DS(on).max}@V_{GS}=10V$	3.55m $\Omega$						
$I_D$	80A						

**Absolute Maximum Ratings**  $T_C = 25^{\circ}C$  unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DSS}$	40	V
Continuous drain current	$I_D$	( $T_C = 25^{\circ}C$ )	80
		( $T_C = 100^{\circ}C$ )	66
Pulsed drain current <sup>1)</sup>	$I_{DM}$	320	A
Gate-Source voltage	$V_{GSS}$	$\pm 20$	V
Avalanche energy <sup>2)</sup>	$E_{AS}$	121	mJ
Power Dissipation	$P_D$	65	W
Storage Temperature Range	$T_{STG}$	-55 to +150	$^{\circ}C$
Operating Junction Temperature Range	$T_J$	-55 to +150	$^{\circ}C$

**Thermal Characteristics**

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.9	$^{\circ}C/W$
Thermal Resistance, Junction-to-Ambient <sup>3)</sup>	$R_{\theta JA}$	65	$^{\circ}C/W$

**Package Marking and Ordering Information**

Device	Device Package	Marking	Units/Reel
VST04N035-T2	TO-252	VST04N035-T2	2500

**Electrical Characteristics**
 $T_J = 25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
<b>Static characteristics</b>						
Drain-source breakdown voltage	$BV_{DSS}$	$V_{GS}=0\text{ V}, I_D=250\mu\text{A}$	40	---	---	V
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.1	---	2.3	V
Drain-source leakage current	$I_{DSS}$	$V_{DS}=40\text{ V}, V_{GS}=0\text{ V}, T_J = 25^\circ\text{C}$	---	---	1	$\mu\text{A}$
		$V_{DS}=40\text{ V}, V_{GS}=0\text{ V}, T_J = 150^\circ\text{C}$	---	---	10	mA
Gate leakage current, Forward	$I_{GSSF}$	$V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$	---	---	100	nA
Gate leakage current, Reverse	$I_{GSSR}$	$V_{GS}=-20\text{ V}, V_{DS}=0\text{ V}$	---	---	-100	nA
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10\text{ V}, I_D=40\text{ A}, T_J = 25^\circ\text{C}$	---	3.25	3.55	m $\Omega$
Forward transconductance	$g_{fs}$	$V_{DS} = 20\text{ V}, I_D=30\text{A}$	---	60	---	S
<b>Dynamic characteristics</b>						
Input capacitance	$C_{iss}$	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V},$ $f = 1\text{MHz}$	---	2038	---	pF
Output capacitance	$C_{oss}$		---	762.6	---	
Reverse transfer capacitance	$C_{rss}$		---	68.4	---	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 20\text{V}, V_{GS}=15\text{V}, I_D = 40\text{ A}$	---	9	---	ns
Rise time	$t_r$		---	9	---	
Turn-off delay time	$t_{d(off)}$		---	74.4	---	
Fall time	$t_f$		---	19.6	---	
Gate resistance	$R_g$	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	---	1.8	---	$\Omega$
<b>Gate charge characteristics</b>						
Gate to source charge	$Q_{gs}$	$V_{DS}=32\text{ V}, I_D=40\text{A},$ $V_{GS}= 10\text{ V}$	---	5.82	---	nC
Gate to drain charge	$Q_{gd}$		---	7.1	---	
Gate charge total	$Q_g$		---	34.5	---	
Gate plateau voltage	$V_{plateau}$		---	3.1	---	V
Output Charge	$Q_{oss}$	$V_{DS}=32\text{ V}, V_{GS}= 0\text{V}$	---	31	---	nC
<b>Drain-Source diode characteristics and Maximum Ratings</b>						
Continuous Source Current	$I_S$		---	---	54	A
Pulsed Source Current <sup>4)</sup>	$I_{SM}$		---	---	216	A
Diode Forward Voltage	$V_{SD}$	$V_{GS}=0\text{V}, I_S=40\text{A}, T_J=25^\circ\text{C}$	---	---	1.2	V
Reverse Recovery Time	$t_{rr}$	$I_S=40\text{A}, di/dt=100\text{A}/\mu\text{s},$ $T_J=25^\circ\text{C}$	---	36	---	ns
Reverse Recovery Charge	$Q_{rr}$		---	37.9	---	nC

**Notes:**

- 1: Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2:  $V_{DD}=20\text{V}, V_{GS}=10\text{V}, L=0.5\text{mH}, I_{AS}=22\text{A}, R_G=25\Omega,$  Starting  $T_J=25^\circ\text{C}$ .
- 3: The value of  $R_{thJA}$  is measured by placing the device in a still air box which is one cubic foot.
4. Pulse Test: Pulse Width  $\leq 300\ \mu\text{s}$ , Duty Cycle  $\leq 2\%$ .

**Electrical Characteristics Diagrams**

Figure 1. Typ. Output Characteristics

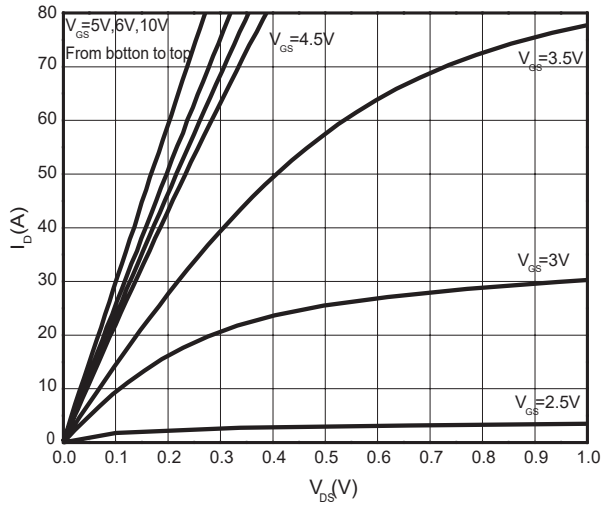


Figure 2. Transfer Characteristics

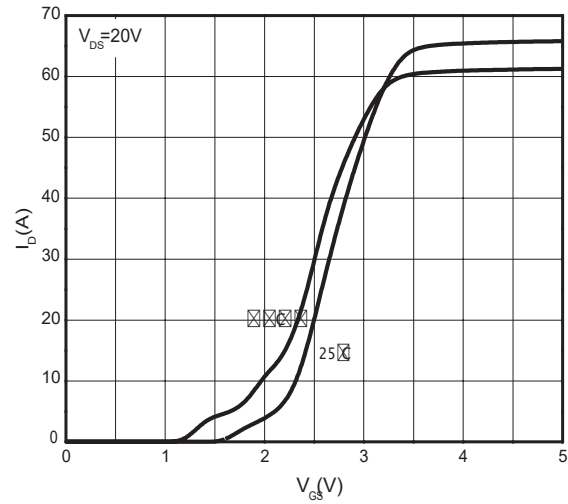


Figure 3. On-Resistance Variation vs. Drain Current

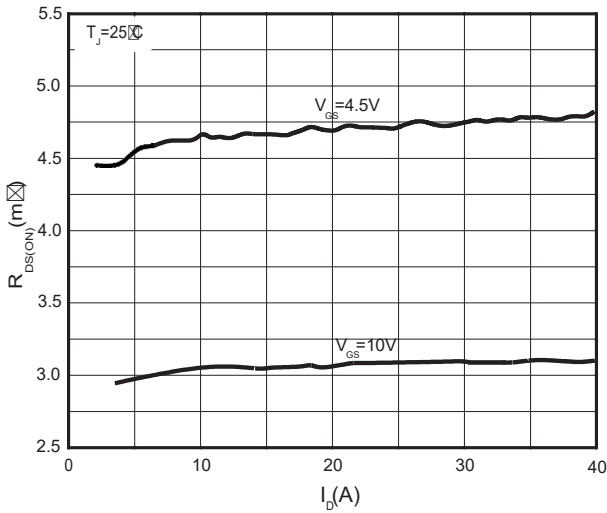


Figure 4. Threshold Voltage vs. Temperature

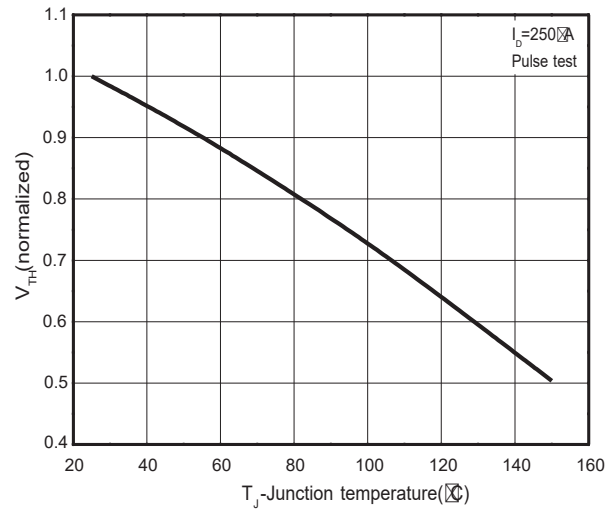


Figure 5. Breakdown Voltage vs. Temperature

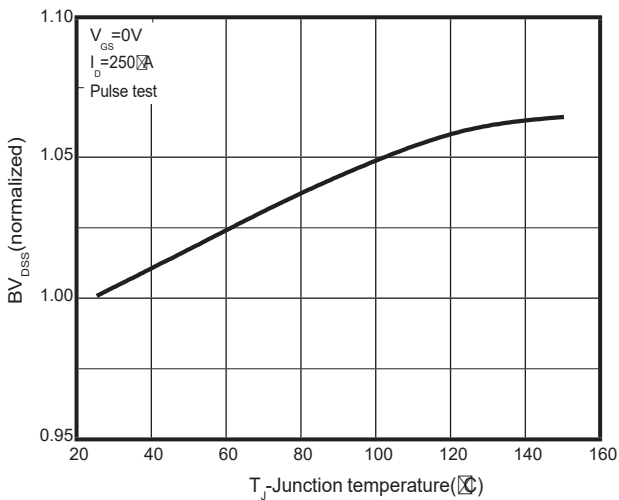


Figure 6. On-Resistance vs. Temperature

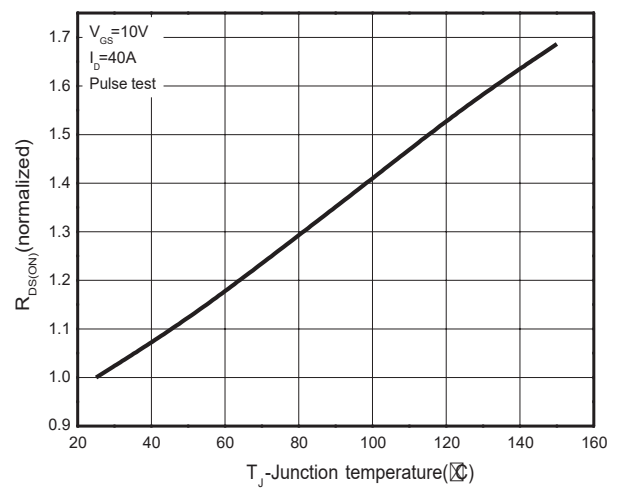


Figure 7. Rds(on) vs. Gate Voltage

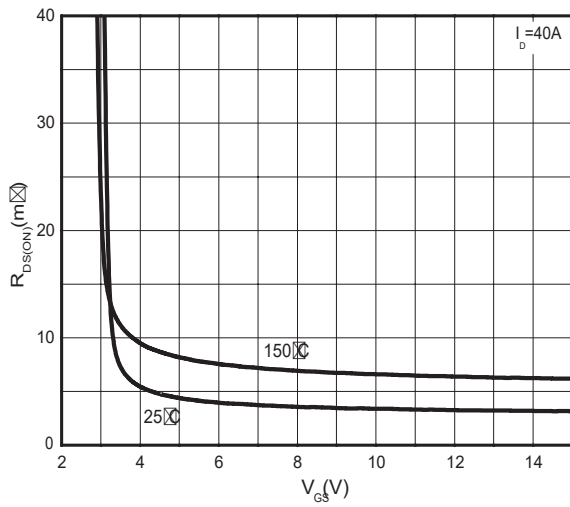


Figure 8. Body-Diode Characteristics

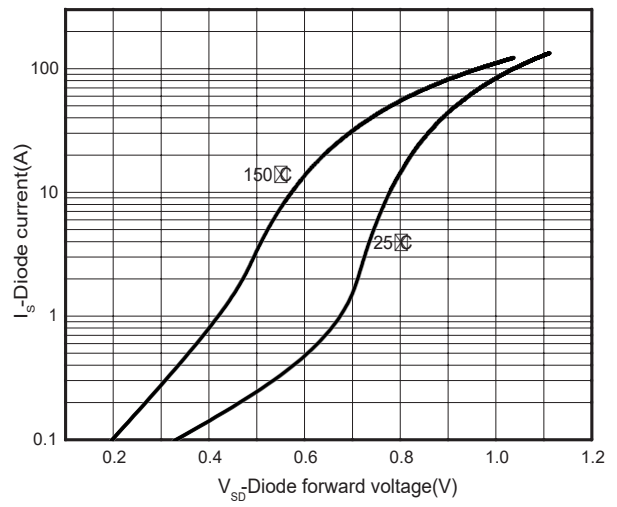


Figure 9. Capacitance Characteristics

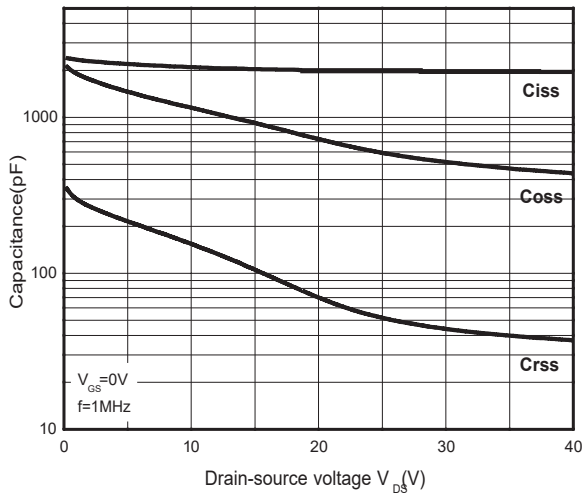


Figure 10. Gate Charge Characteristics

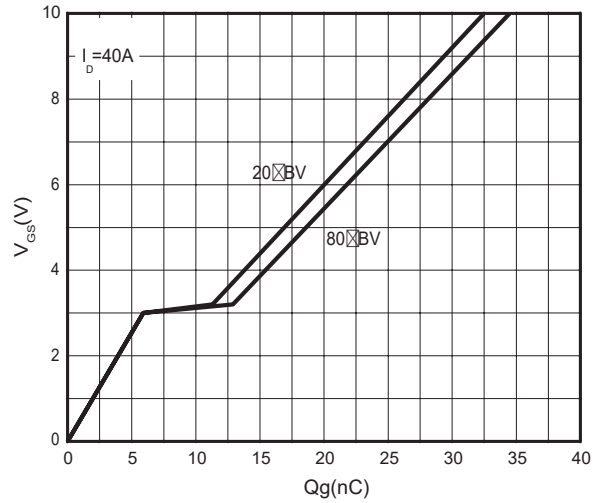


Figure 11. Drain Current Derating

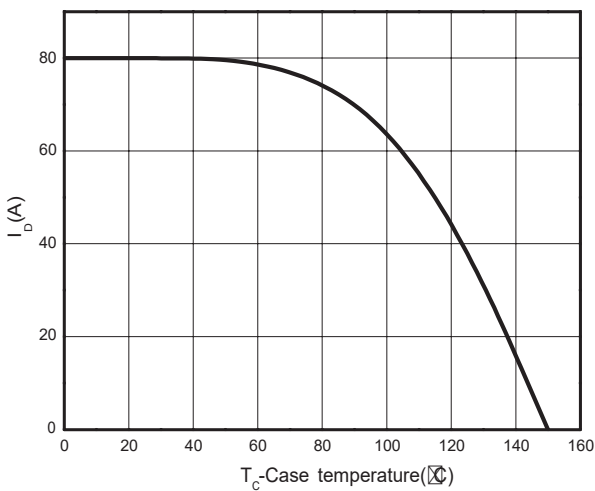


Figure 12. Power Dissipation vs. Temperature

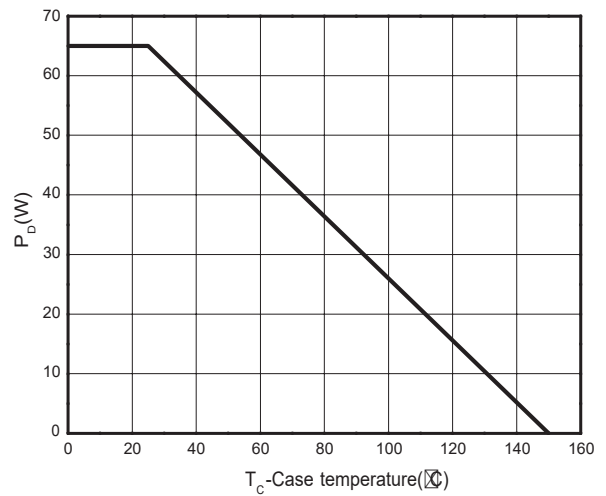
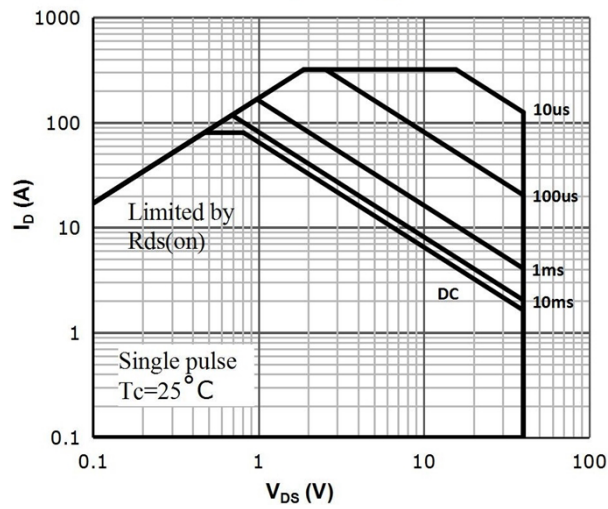
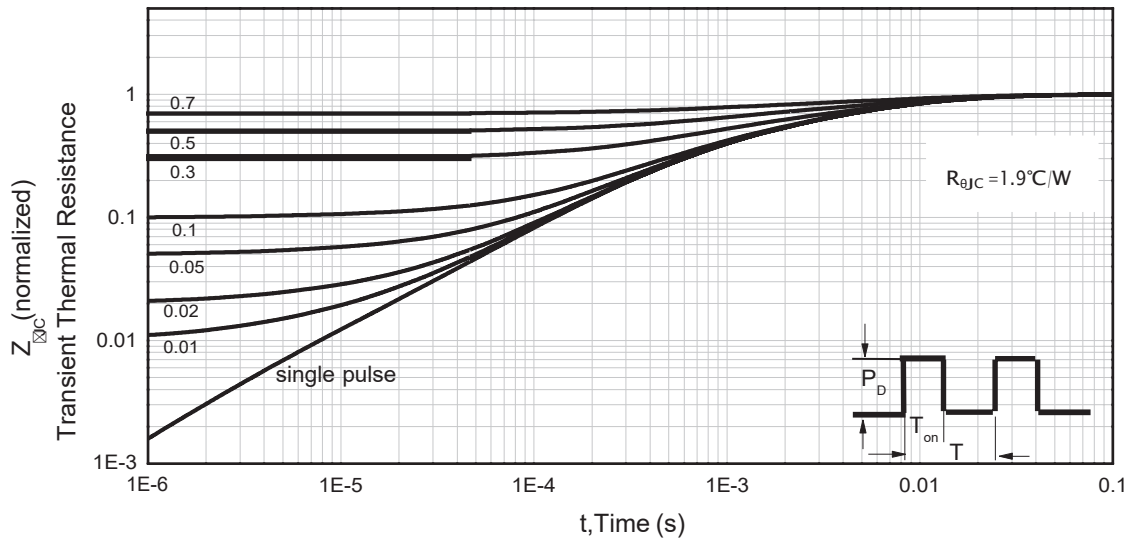
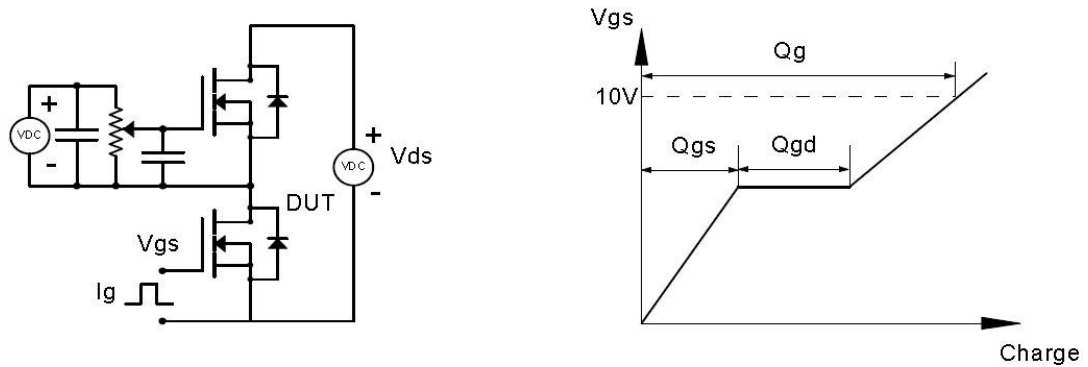
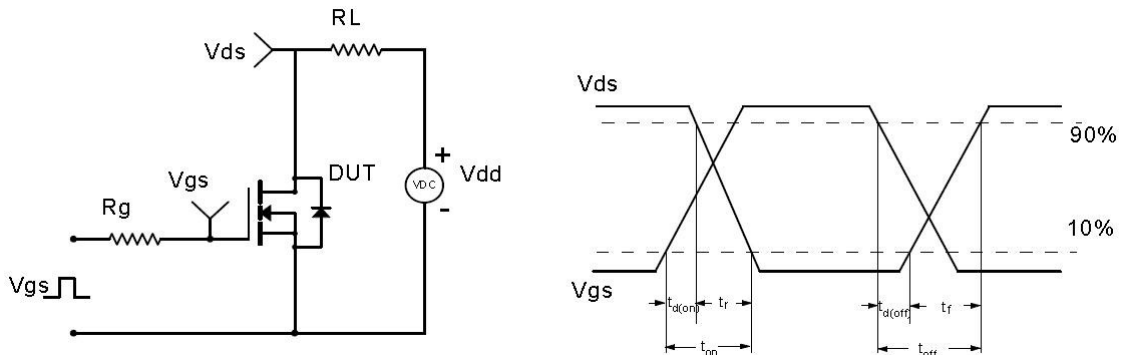
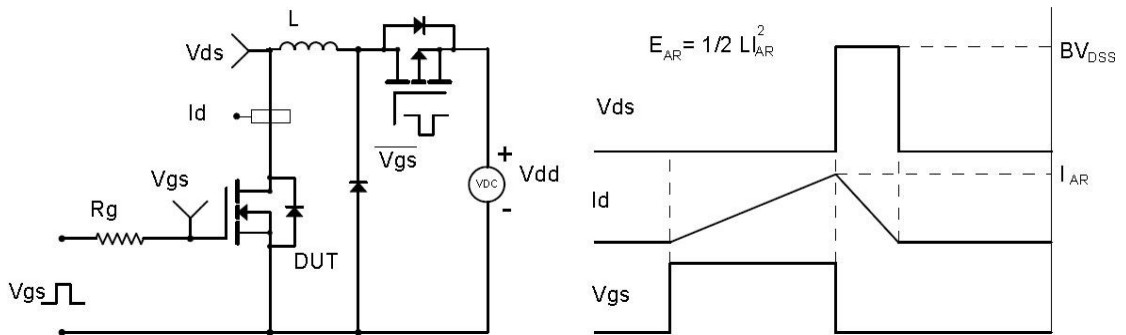


Figure 13: Safe Operating Area


 Figure 14. Normalized Maximum Transient Thermal Impedance ( $R_{thJC}$ )


**Test Circuit & Waveforms**
**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
